

China Electronic Component Center Laboratory

Test Report

Applicant : 新思科电子
Part Number : XC2S50E-6PQG208I
Manufacturer : XILINX
Date Code : 1443
Package : QFP-208
Quantity Submitted : 85 pieces
Quantity Tested : 85 pieces
Date of Received : 2018/04/27
Date of Tested : 2018/04/27--2018/04/28

General Conclusion

Test Level	Total(pcs)	Pass(pcs)	Fail(pcs)	Test Requirement
Functional Test	85	85	0	ODM's specification

85 pieces devices were performed KFT, with all passed.

Approved by: Chen Tian

Technical supervisor: Peng Qing

Engineer: Chen Kaiju

Report reviewer: Zhang Siwei

Project to undertake (unit): China Electronic Component Center Laboratory

Note: This report refers only to the specimen(s) submitted to test, and is invalid if used separately.

Key Functional Testing (KFT):

I. Test Purpose

To detect device function.

II. Test Environment

Environment Temperature: $(25 \pm 2)^{\circ}\text{C}$;

Environment Humidity: $(55 \pm 5)\%$ RH.

III. Test Equipment

As shown in the testing process.

IV. Test Standard

《CECC-STANDARD》 and 《JEDEC-STANDARD》 .

V. Test Basis

《Xilinx XC2S50E》 .

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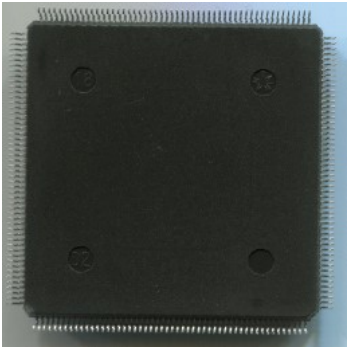
VI. Test Procedure and Analysis

1. Packaging Inspection

Package:	☐ PVC Tube ☒ Tray ☐ Reel ☐ Anti-static bags ☐ Plastic bags ☐ Vacuum-sealed ☐ Others
Complete labeling	No
Humidity indicator cards (HIC):	No
Moisture barrier bag and desiccant pouches:	No

2. Incoming Description

One sample visual inspection was as shown without special requirements.

Top view	Bottom view
	

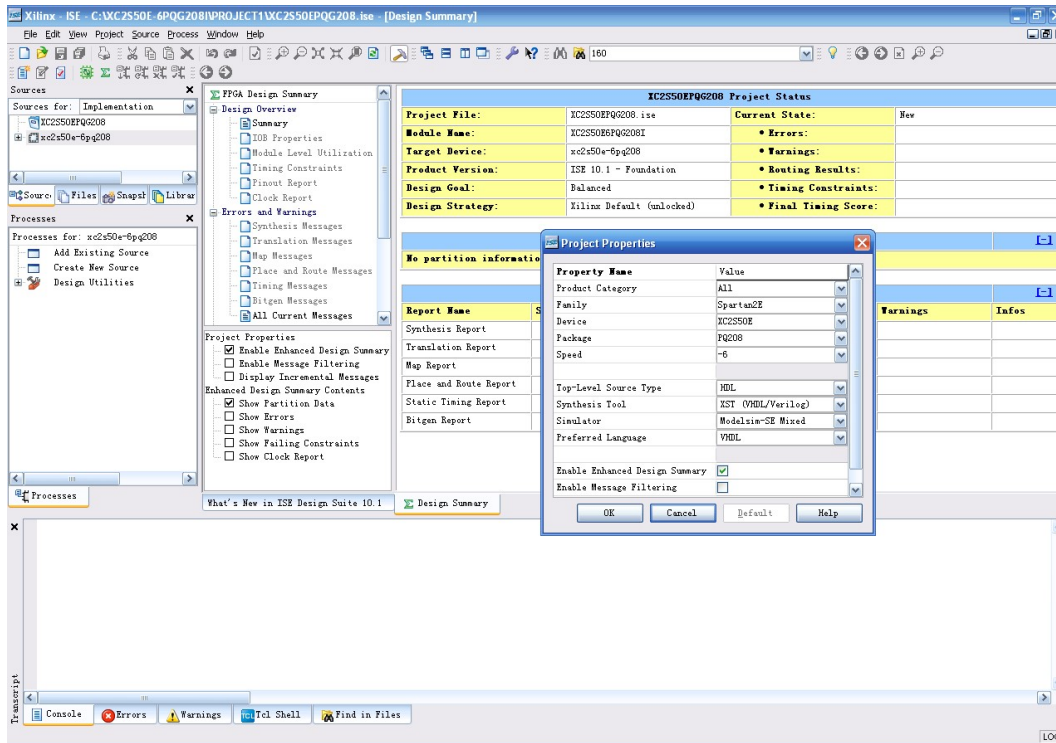
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3. Functional Test and Analysis

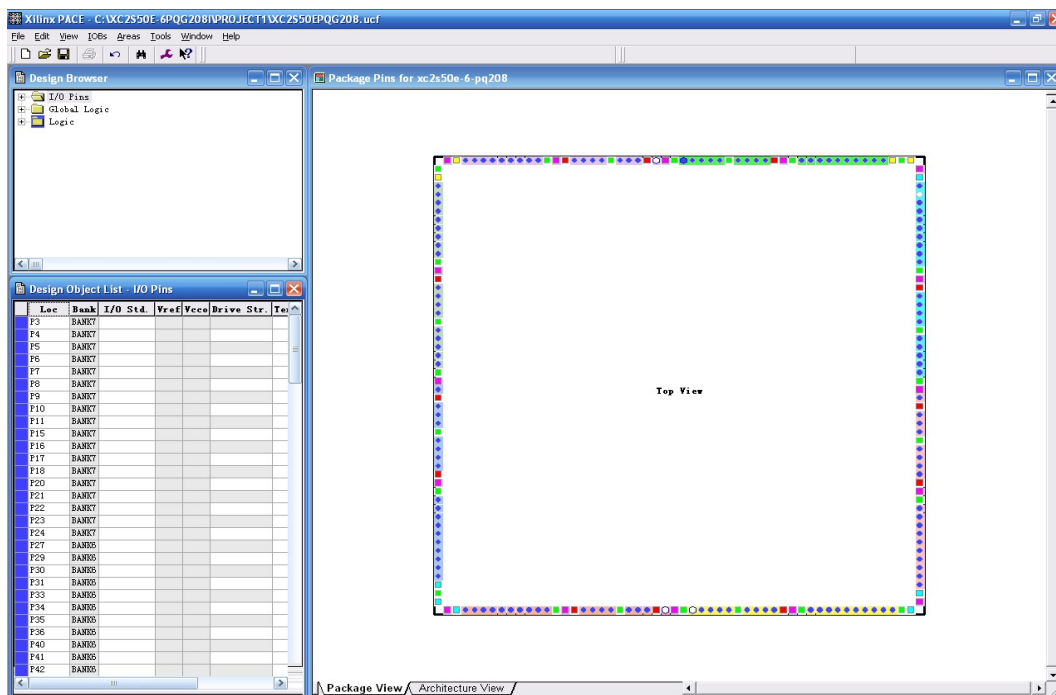
85 pieces devices were performed KFT, with all passed.

Test diagrams are as follows:

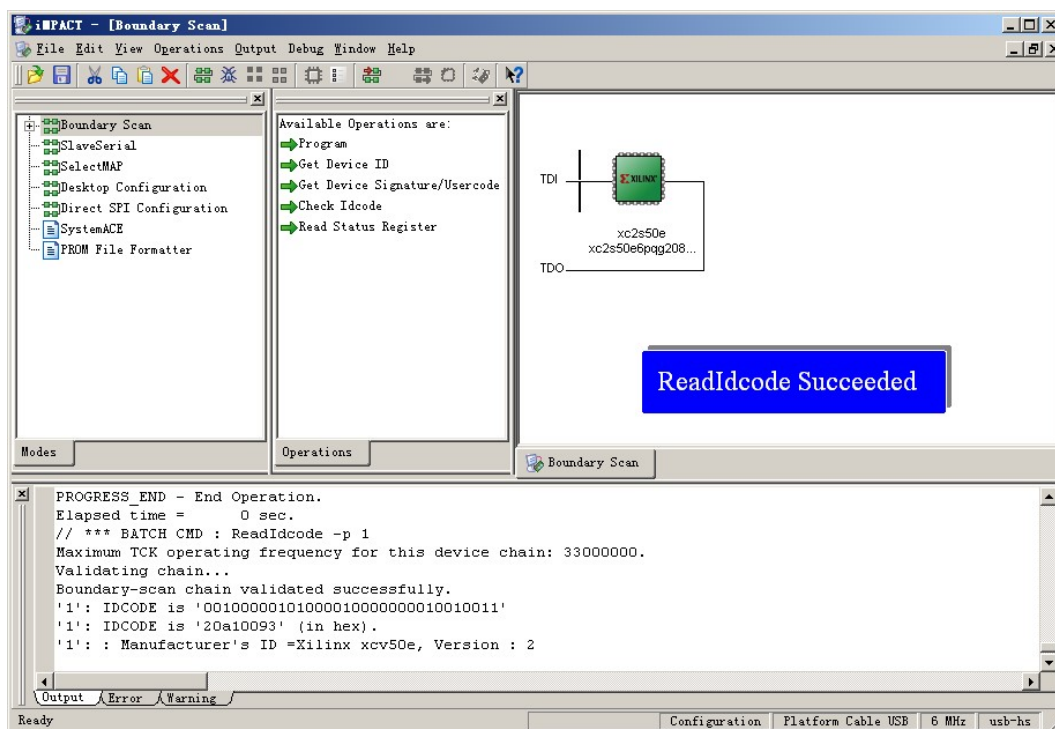
Select device



PIN configuration



Read ID code succeeded

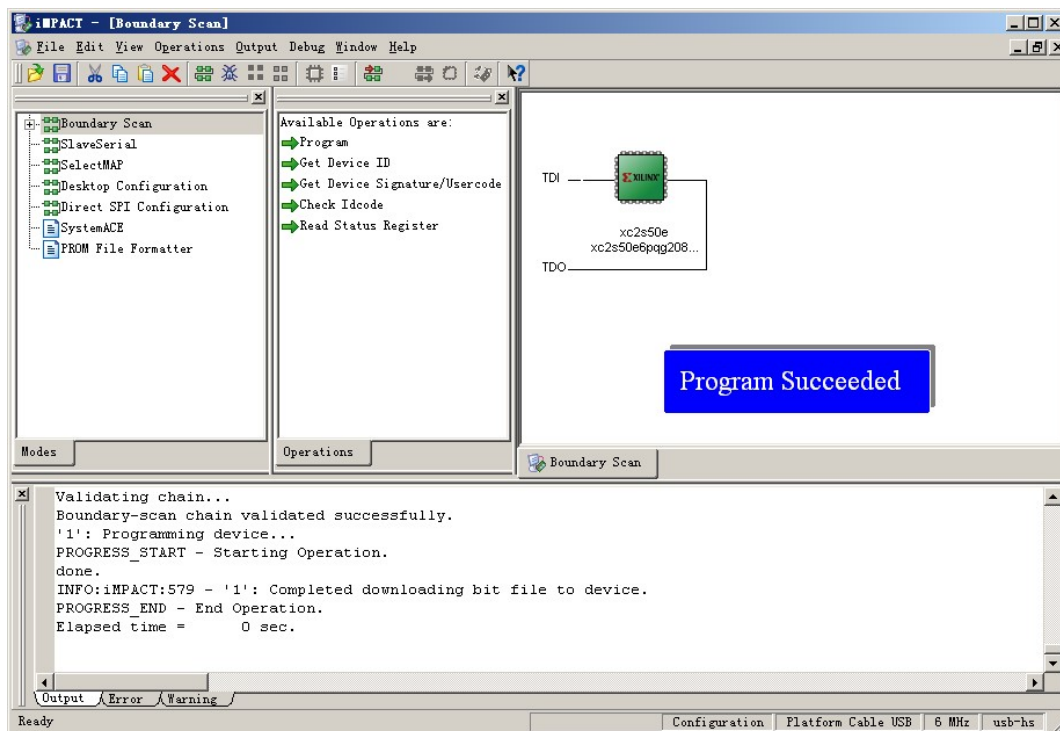


'1': IDCODE is '00100000101000010000000010010011'

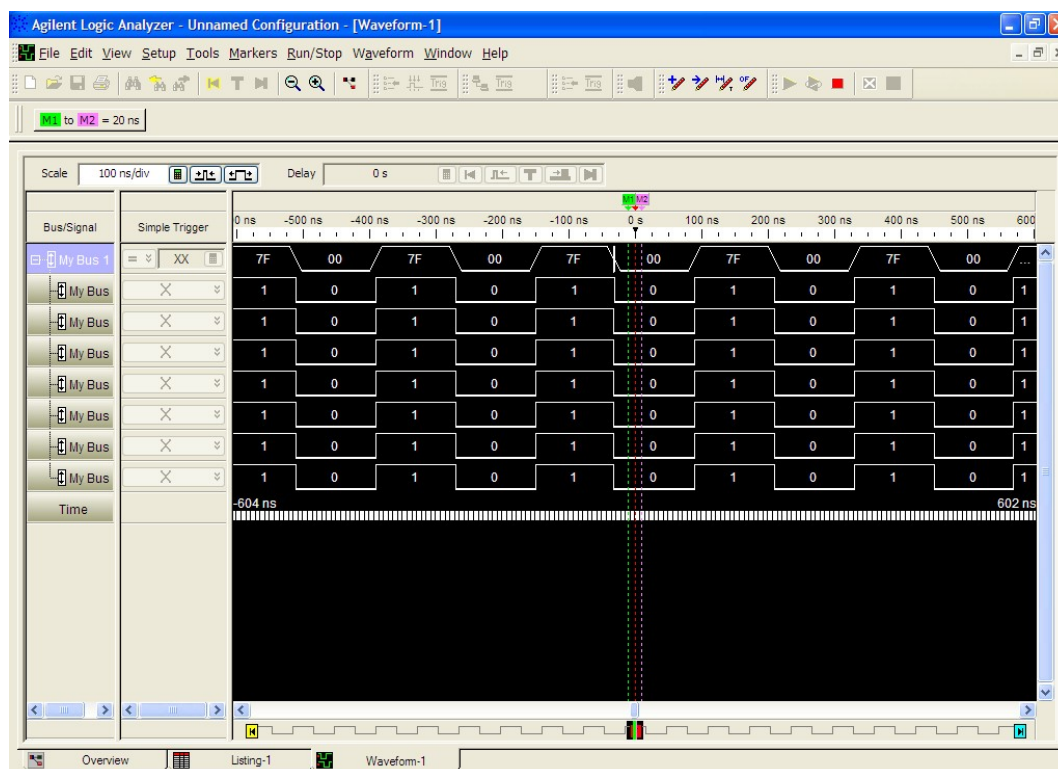
'1': IDCODE is '20a10093' (in hex).

'1': : Manufacturer's ID =Xilinx xcv50e, Version : 2

Program succeeded



Functional verification (Functional verification Output waveform)



Appendix I

Optional items:

- ☐ Visual Inspection
- ☐ X-Ray Inspection
- ☐ Chemical Decapsulation
- ☐ Failure Analysis
- ☐ Reliability Analysis
- ☐ Solderability Analysis
- ☐ Level I Authenticity Inspection and Verification (AIV)
- ☐ Level II Direct Current Characteristics testing (DCCT)
- ☒ Level III Key Functional Testing (KFT)
- ☐ Level IV Full Functional Characteristics Testing (FFCT)
- ☐ Level V Alternating Current Characteristics testing (ACCT)
- ☐ Other Items

Test Items Description Reference: <http://www.cecclab.com/en/icmenu.asp?id=101&id1=101>

Brief introduction of CECC

China Electronic Component Center Lab abbreviated as CECC, with the development of more than 15 years, we are setting up 4 engineering centers for semiconductor innovation and 2 factories for batch IC testing in Shenzhen, Xi'an, Wuxi and Jinan. CECC has been established the pleasure and firm cooperation with IC design house, distributor, EMS, etc.

CECCLab WeChat ID

